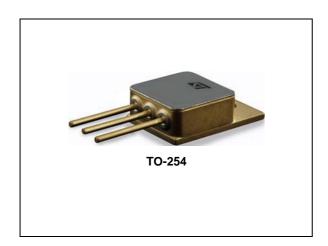


STPS40100HR

Aerospace 2 x 20 A - 100 V Schottky rectifier

Datasheet - production data



Features

Forward current: 2 x 20 A

Repetitive peak voltage: 100 V

• Low forward voltage drop: 0.9 V

Maximum junction temperature: 175 °C

• Negligible switching losses

Low capacitance

High reverse avalanche surge capability

Hermetic packages

• Target radiation qualification:

- 150 krad (Si) low dose rate

- 1 Mrad high dose rate

ESCC qualified

Description

This power Schottky rectifier is designed and packaged to comply with the ESCC5000 specification for aerospace products. Housed in hermetically sealed packages both surface mount and through hole, it is ideal for use in applications for aerospace and other harsh environments.

The STPS40100HR is intended for use in medium voltage application and particularly, in high frequency circuits where low switching losses and low noise are required.

Table 1. Device summary

Order code	ESCC detailed specification	Quality level	Package	I _{F (AV)}	V _{RRM}	T _j (max)	V _F (max)
STPS40100C2FY1	-	Engineering model	TO-254 2 x 20		100	175	0.9
STPS40100C2FYT	5106/019/01	ESCC flight					

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1 Characteristics

Table 2. Absolute maximum ratings

Symbol	Characteristic	Value	Unit
I _{FSM}	Forward surge current (per diode) ⁽¹⁾	300	Α
V _{RRM}	Repetitive peak reverse voltage ⁽²⁾	100	V
I _{RRM}	Repetitive peak reverse current ⁽³⁾	1	А
I _o	Average output rectified current (50% duty cycle): ⁽⁴⁾ , ⁽⁵⁾ per diode per device	20 40	А
I _{F(RMS)}	Forward rms current (per diode)	30	А
T _{OP}	Operating temperature range ⁽⁶⁾ (case temperature)	-65 to +175	°C
T _J	Junction temperature	+175	°C
T _{STG}	Storage temperature range ⁽⁶⁾	-65 to +175	°C
T _{SOL}	Soldering temperature: For TO-254 ⁽⁷⁾	+260	°C
dV/dt	Critical rate of rise of reverse voltage	10000	V/µs

- 1. Sinusoidal pulse of 10 ms duration
- 2. Pulsed, duration 5 ms, F = 50 Hz
- 3. Pulsed, duration 2 μ s, F = 1 kHz
- 4. For $T_{case} \ge +132^{\circ}C$ per device and $T_{case} \ge +148^{\circ}C$ per diode, derate linearly to 0 A at +175°C.
- 5. The "per device" ratings apply only when both anode terminals are tied together.
- For devices with hot solder dip lead finish all testing performed at T_{amb} > +125 °C are carried out in a 100% inert atmosphere.
- 7. Duration 10 seconds maximum at a distance of not less than 1.5 mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.

Table 3. Thermal resistance

Symbol	Characteristic	Value	Unit
R _{th(j-c)} (1)	Thermal resistance, junction to case per diode per device	1.5 1.2	°C/W

1. Package mounted on infinite heatsink

STPS40100HR Characteristics

Table 4. Electrical measurements at ambiant temperature (per diode), T_{amb} = 22 ±3 °C

Symbol	Characteristic	MIL-STD-750	D-750 Test conditions		Values	
	Citaracteristic	test method	rest conditions	Min.	Max.	Units
I _{R1}	Reverse current	4016	DC method, V _R = 100 V	-	30	μA
I _{R2}	Reverse current	4010	DC method, V _R = 50 V	-	5	μA
V _{F1} ⁽¹⁾			Pulse method, I _F = 5 A	-	610	mV
V _{F2} ⁽¹⁾	Forward voltage	4011	Pulse method, I _F = 10 A	-	730	mV
V _{F3} ⁽¹⁾			Pulse method, I _F = 20 A	-	900	mV
С	Capacitance	4001	V _R = 10 V, F = 1 MHz	-	1	nF
Z _{th(j-c)} ⁽²⁾	Relative thermal impedance, junction to case	3101	$I_H = 15 \text{ to } 40 \text{ A}, t_H = 50 \text{ ms}$ $I_M = 50 \text{ mA}, t_{md} = 100 \mu\text{s}$	Calculate ΔV _F ⁽³⁾		°C/W

^{1.} Pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$

Table 5. Electrical measurements at high and low temperatures (per diode)

Symbol Charac	Characteristic	MIL-STD-750	Test conditions ⁽¹⁾	Values		Units
	Cital acteristic	test method	rest conditions.	Min.	Max.	Oints
I _{R1}	Royarca current	4016	T_{case} = +125 (+0, -5) °C DC method, V_R = 100 V	-	20	mA
I _{R2}	Reverse current		T_{case} = +125 (+0, -5) °C DC method, V_R = 50 V	-	7.5	mA
V _{F2} ⁽²⁾			T_{case} = +125 (+0, -5) °C pulse method, I_F = 10 A	-	660	mV
V (2)	Forward voltage	4011	T_{case} = +125 (+0, -5) °C pulse method, I_F = 20 A	-	850	mV
V _{F3} ⁽²⁾		$\Gamma_{\text{case}} = -55 \text{ (+5, -0) °C}$ bulse method, $I_{\text{F}} = 20 \text{ A}$	950	mV		

^{1.} Read and record measurements shall be performed on a sample of 5 components with 0 failures allowed. Alternatively a 100% inspection may be performed.

^{2.} Performed only during screening tests parameter drift values (initial measurements for HTRB), go-no-go.

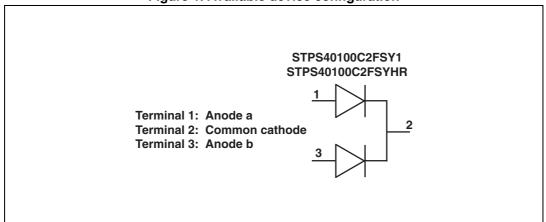
^{3.} The limits for ΔVF shall be defined by the manufacturer on every lot in accordance with MIL-STD-750 Method 3101 and shall guarantee the $R_{th(j-c)}$ limits specified in maximum ratings.

^{2.} Pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$

Configurations STPS40100HR

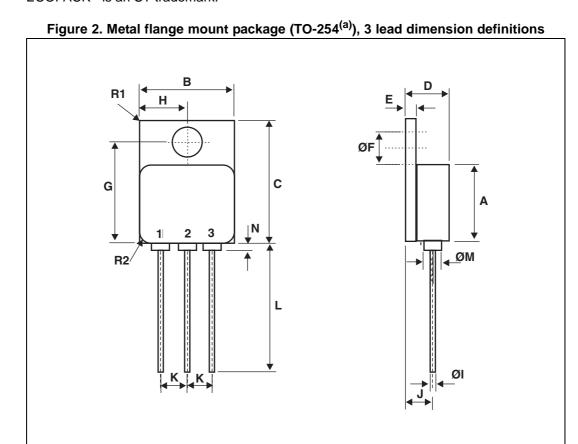
2 Configurations

Figure 1. Available device configuration



3 Package Information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.



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a. The terminal identification is specified by the device configuration. See *Figure 1* for terminal connections

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Table 6. Metal flange mount package (TO-254), 3-lead dimension values

Deference	Dimension in	n millimetres	Dimlension in inches		
Reference	Min.	Max.	Min.	Max.	
А	13.59	13.84	0.535	0.545	
В	13.59	13.84	0.535	0.545	
С	20.07	20.32	0.790	0.800	
D	6.3	6.7	0.248	0.264	
E	1	3.9	0.039	0.154	
ØF	3.5	3.9	0.138	0.154	
G	16.89	17.4	0.665	0.685	
Н	6.86	BSC	0.270 BSC		
ØI ⁽¹⁾	0.89	1.14	0.035	0.045	
J	3.81	BSC	0.150 BSC		
K	3.81	BSC	0.150) BSC	
L	12.95	14.5	0.510	0.571	
ØM	3.05 Typ.		0.120	Тур.	
N	-	0.71	-	0.028	
R1 ⁽²⁾	-	1	-	0.039	
R2 ⁽³⁾	1.65	Тур.	0.0	065	

^{1. 3} locations

^{2.} Radius of heatsink flange corner - 4 locations

^{3.} Radius of body corner - 4 locations



4 Ordering Information

Table 7. Ordering information

Order code	ESCC detailed specification	Package	Lead finish	Comment	Marking ⁽¹⁾	Mass	EPPL	Packing
STPS40100C2FY1	-	TO-254	Gold	Double die - common cathode pin 2	STPS40100C2FY1 + BeO	10	1	Strip pack
STPS40100C2FYT	5106/019/01	10-254	Solder Dip	Double die - common cathode pin 2	510601901+BeO	10	-	

^{1.} Specific marking only. The full marking includes in addition: For the engineering models: ST logo, date code, country of origin (FR). For ESCC flight parts: ST logo, date code, country of origin (FR), ESA logo, serial number of the part within the assembly lot.

Contact ST sales office for information about the specific conditions for tape and reel packing and for products in die form.

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Revision history STPS40100HR

5 Revision history

Table 8. Document revision history

Date	Revision	Changes
26-Mar-2010	1	Initial release.
19-Mar-2014	2	Updated Table 1: Device summary and Table 7: Ordering information.

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